Intergrated Correlative Light and Electron Microscopy

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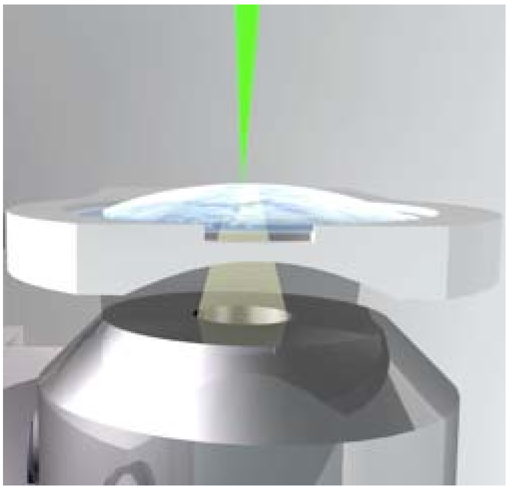
DELMIC introduces the SECOM platform, a device that integrates a fluorescence microscope with a scanning electron microscope (SEM). The system may be retrofitted on almost all commercially available SEMs.
This integrated solution makes correlative microscopy easier, faster and more accurate. DELMIC has created a proprietary solution for using immersion oils in vacuum, thereby allowing the integration of high-NA optics. The integrated solution furthermore allows for automatic overlays between the fluorescence and electron images, accounting for scaling, rotation and even non-linear effects, creating an overlay with unprecedented accuracy.
This workshop will introduce the SECOM platform as a novel way of doing correlative microscopy.
The workshop will cover the specifications and design of the platform and some of the areas of application.
Finally, the current challenges still facing integrated correlative microscopy will be discussed.



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